

ESA-CNES Final Presentation Days 2013

Programme - Wednesday 5th June 2013

Conference Room: Newton 2

Time	Speaker	Organisation	Title
9:30 Welcome			
9:40	Matthieu CAUSSANEL	Perpignan University	Radiation-induced attenuation on commercial optical fibers.
10:00	Cédric VIRMONTOIS, Alain BARDOUX	CNES	Space Radiations Induced Permanent and Single Event Effects in 4Mpixel global pipelined shutter CMOS Image Sensors
10:20	Christelle DENEAU	IES – Montpellier University	Calibration of the OSL sensors and feasibility study of a new generation dosimeter
10:40-10:55 Question time / Coffee Break			
10:55	Emma MARTIN	CNES	Space Radiation Induced Dark Current Degradation in 5T Pinned Photodiode 0.18 µm CMOS Image Sensors
11:15	Anne SAMARAS	TRAD	Linear integrated circuit cumulated dose test representativeness for high energy electron environment applications
11:35-11:50 Question time / Coffee Break			
11:50	Athina VAROTSOU	TRAD	Shielding Geometry Effect on SEE Prediction Using the New OMERE Release: JASON-2 Mission Case Study
12:10	Anne SAMARAS	TRAD	Single event upset cross section dose dependence on 90nm SRAM

Lunch 12:30-13:30

Time	Speaker	Organisation	Title
13:30	Aleksandar Jaksic	Tyndall	Recent results on Radfets at various dose rate
13:50	Gonzalo Fernandez Romero	Alter Spain	TID test results on linear devices 36 versus 360rad/h
14:05	Gonzalo Fernandez Romero	Alter Spain	Radiation tests under controlled temperature and vacuum conditions: why and how
14:15-14:30 Question time / Coffee Break			
14:30	Anne Samaras	TRAD	Radiation results on optocouplers: TID, proton and neutron induced DD, proton induced SETs
14:55	Anne SAMARAS	TRAD	TID characterisation of power-up behaviour for FPGAs
15:10	Dominique Hervé	SODERN	SEE, TID and DD results on Onsemi HAS2 APS
15:40	François-Xavier Guerre	HIREX	New version of the SEU monitor
15:55-16:10 Question time / Coffee Break			
16:10	Athina VAROTSOU	TRAD	TID and SEE characterisation of 40MHz CFPT9006 oscillator from Rakon
16:20	Andrew Chugg	MBDA	Laser SEE test results on linear ICs and photodiode
16:40	Gianluca Furano	ESA ESTEC	Radiation tests of COTS components in ESA – TI CAN transceiver and Telefunken POL

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Programme - THURSDAY 6th June 2013

Conference Room: Newton 2

Time	Speaker	Organisation	Title
9:30	Patricia Gonçalves	LIP	Characterisation of RADFET dosimeters
9:45	Gonzalo Fernandez Romero	ALTER	400 Krad TID test results on parts used in power systems for JUICE
10:05	Mark Robbins	SSTL	Displacement Damage Test Guideline for imagers (CCP, APS, and IR imager arrays)
10:25	Mirko Rostewitz	TESAT	Single Event Effect Analysis on DC and RF operated AlGaN/GaN HEMTs
10:45 – 11:00 Question time / Coffee Break			
11:00	Aminata Carvalho, Christian Binois	EADS-Astrium Elancourt	Statistical SEGR radiation test method study in power MOSFETs
11:20	Arto Javanainen	Jyväskylä Univ. (RADEF)	SEGR study - Effects of ion species, energy and oxide thickness
11:40-11:55 Question time / Coffee Break			
11:55	Ari Virtanen	Jyväskylä Univ.	RADEF irradiation test facility status report
12:05	Marc Loiselet	Univ.Catholique de Louvain	UCL irradiation test facility status report
12:15	Wojtek Hajdas	Paul Scherrer Inst.	PSI irradiation test facility status report

Lunch 12:30-13:30

Time	Speaker	Organisation	Title
13:30	Marta Bagatin	Univ. Padova	Studies of radiation effects in new generations of non-volatile memories
13:55	Kai Grümann, Martin Herrmann, Fritz Gliem, Hagen Schmidt	IDA & EADS-Astrium	Radiation Testing Of Candidate Memory Devices, DDR3 and NAND-Flash
14:20	C. Poivey	ESA	Displacement Damage Testing of Linear Devices For ESCC Test Guidelines Definition
14:35 -14:50 Question time / Coffee Break			
14:50	Sophie Duzellier	ONERA	Dose Rate Effect on Bipolar Circuits Degradation
15:10	Marco d'Alessio	ESA	Analysis of the TDM and DLR Phoenix GPS flight data on Proba2
15:30-15:45 Question time / Coffee Break			
15:45	Ana Keating	LIP	Presentation of the CODES simulation tool
16:05	Alessandra Costantino	ESA ESTEC	Proton and Co60 radiation test data in recent COTS and radiation-tolerant optocouplers